

Dr. Tobias Schüllli is an experimental physicist and material scientist with a strong expertise in the application of x-ray diffraction to materials and nanostructures and the construction of large scale instruments. He has been invited as a speaker or plenary lecturer at many international conferences.

Tobias Schüllli obtained his PhD at the University of Linz at the Institute for semiconductor physics in 2003 supervised by Prof. Guenther Bauer. After a post doc at the CEA Grenoble he joined XENOCS Company in end customer and B2B marketing. In 2006 he returned to CEA to develop *in situ* x-ray scattering methods during growth of semiconductors on Beamline BM32 at The European Synchrotron ESRF. He has been lecturing diffraction and x-ray physics in English, French and German at the University of Linz and at various topical schools. In 2009 Tobias Schüllli was hired as ESRF staff scientist in charge of the conceptual and technical design and construction of the nano diffraction imaging Beamline ID01 and since 2015 he is head of the X-ray Nanoprobes group of the ESRF.